Lecture 12 Introduction to dynamic AFM - point mass approximation

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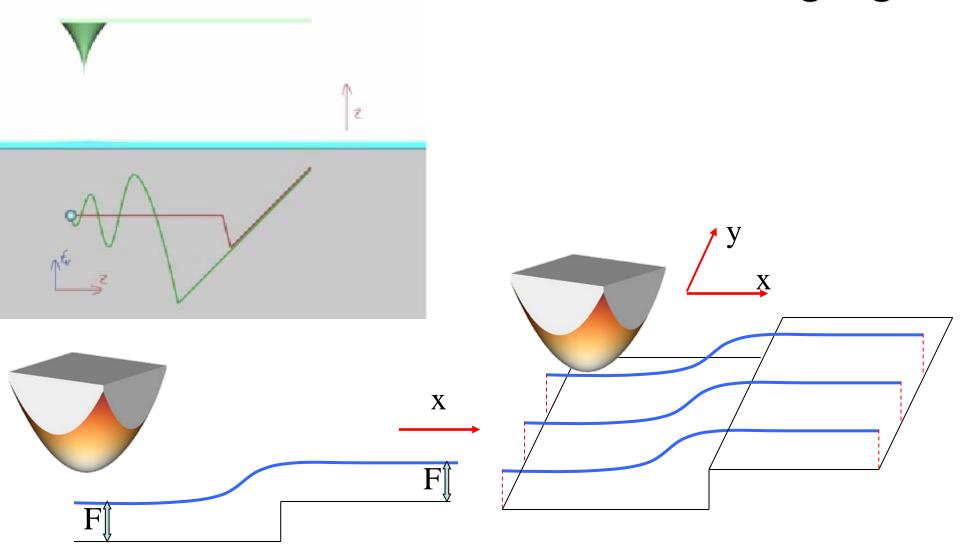
Birck Nanotechnology Center



Contact Mode Imaging \mathbf{X}

First tip contacts surface with some setpoint normal force which is kept constant during the scan

Contact Mode Imaging

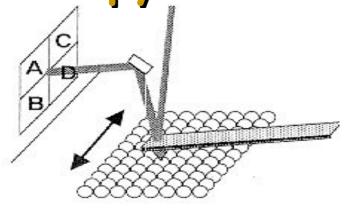


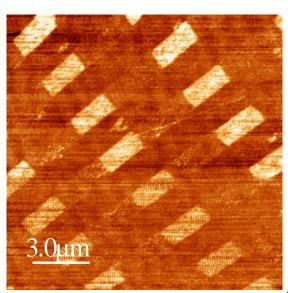
PURDUE

First tip contacts surface with some setpoint normal force which is kept constant during the scan

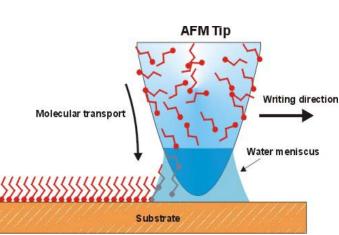
Friction Force Microscopy

- Torsional deflections due to atomic and molecular friction
- Lateral forces are specific
- Applications to nanotribology, probe based lithography

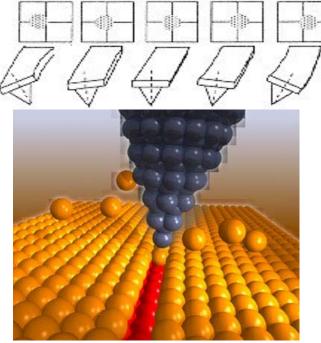




Friction force image of a self assembled monolayer (Riefenberger Group)

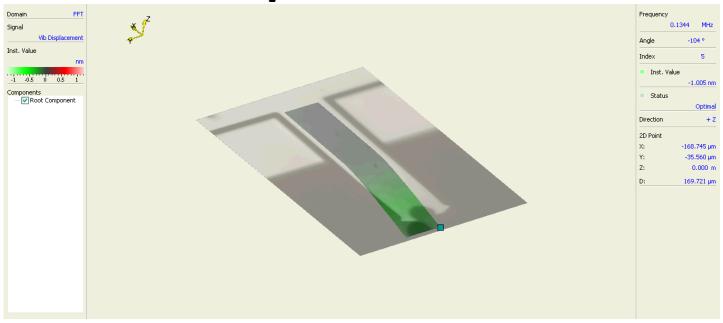


www.chem.nwu.edu/~mkngrp/
Dip-pen lithography



Contact mode oxidation lithography

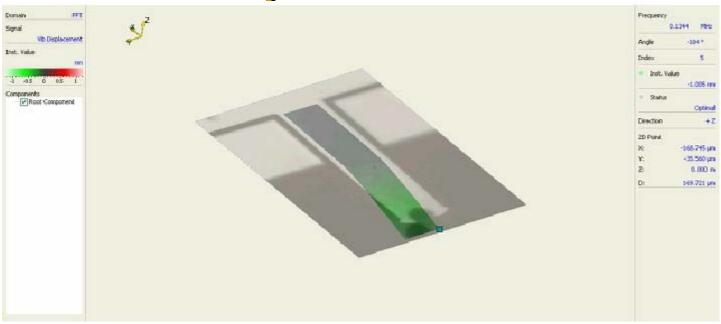
Dynamic AFM



- Cantilever driven near resonance
- The cantilever's resonant frequency, phase and amplitude are affected by short-scale force gradients
- In Amplitude Modulated AFM (AM-AFM) or tapping mode, driving frequency is fixed while cantilever approaches the sample
- In Frequency Modulated AFM (FM-AFM) the phase and amplitude are held constant while approaching the sample



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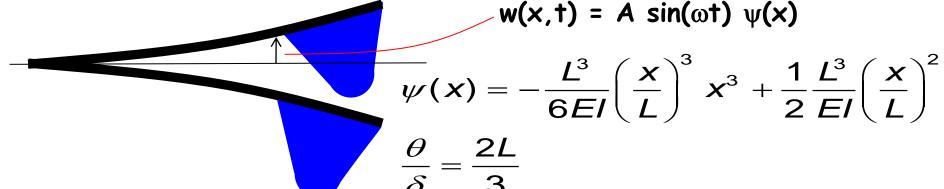
The point mass model

$$w(x,t) = A \sin(\omega t) \psi(x)$$

$$\psi(x) = \cos(\beta \frac{x}{L}) - \cosh(\beta \frac{x}{L}) - \frac{\cos(\beta) + \cosh(\beta)}{\sin(\beta) + \sinh(\beta)} \left[\sin(\beta \frac{x}{L}) - \sinh(\beta \frac{x}{L}) \right]$$

$$\theta/\delta=?$$

Point mass model



- Tip is massive, cantilever inertia negligible
- Replace cantilever by a spring of spring constant= static bending stiffness of lever
- ... Cantilever oscillates such that $\theta/\delta=2L/3$

Point mass model - free oscillations

$$m\ddot{x} = -kx - cx$$

$$m\ddot{x} = -kx - c\dot{x}$$

Damping

coefficient

Spring

$$\frac{\ddot{x}}{\omega_0^2} + x + \frac{1}{\omega_0 O} \dot{x} = 0; w$$

$$\frac{\ddot{x}}{\omega_0^2} + x + \frac{1}{\omega_0 Q} \dot{x} = 0; \text{ with } \quad \omega_0 = \sqrt{\frac{k}{m}}, Q = \frac{m\omega_0}{c} = \frac{\sqrt{mk}}{c}$$

General solution of type

$$x(t) = e^{\lambda t} \Rightarrow \frac{\lambda^2}{\omega_0^2} + 1 + \frac{\lambda}{\omega_0 Q} = 0 \Rightarrow \lambda_{1,2} = -\frac{\omega_0'}{2Q} \pm \omega_0 \sqrt{\frac{1}{4Q^2} - 1}$$

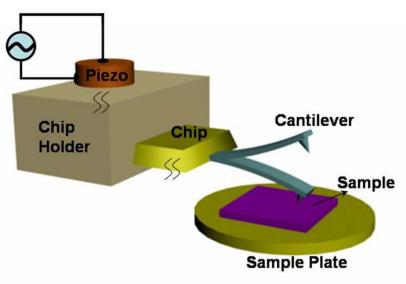
x(t)
Absolute tip motion
$$x(t) = c_1 e^{\lambda_1 t} + c_2 e^{\lambda_2 t}$$
, integration constants to be determined from initial conditions $x(0)$, $\dot{x}(0)$

if $Q > \frac{1}{2}$ Underdamped oscillation

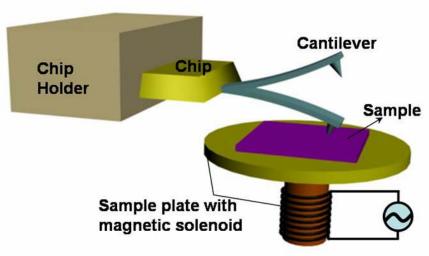
- Damped natural frequency is different from natural frequency
- Q can be regarded as number of oscillation cycles before transients become small



Forced vibrations



a. Acoustic excitation

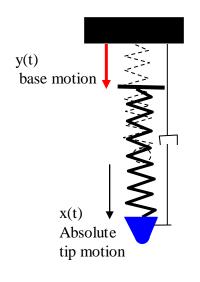


b. Magnetic excitation

- Mechanical (acoustic or piezo excitation)
- Magnetic excitation
- Magnetostrictive excitation
- Photothermal excitation
- Lorentz force excitation
- Ultrasound excitation
- Direct piezoelectric excitation

Response of acoustically excited levers

$$m\ddot{x} = -k(x - y) - c\dot{x}$$



Acoustic (inertial or piezo)

$$\frac{\ddot{x}}{\omega_0^2} + x + \frac{1}{\omega_0 Q} \dot{x} = y(t); \text{ with } \omega_0 = \sqrt{\frac{k}{m}}, Q = \frac{m\omega_0}{c}$$

Measured motion z(t) = x(t) - y(t)

$$\frac{z}{\omega_0^2} + z + \frac{1}{\omega_0 Q} \dot{z} = -\frac{y}{\omega_0^2} - \frac{1}{\omega_0 Q} \dot{y}$$

$$y(t) = Y_0 \sin(\omega t)$$

$$z^p(t) = A \sin(\omega t - \phi_{inertial})$$

$$|H_{inertial}(\omega)| = \frac{A}{Y_0} = \left(\frac{r^4 + (r/Q)^2}{(1 - r^2)^2 + (r/Q)^2}\right)^{1/2}$$

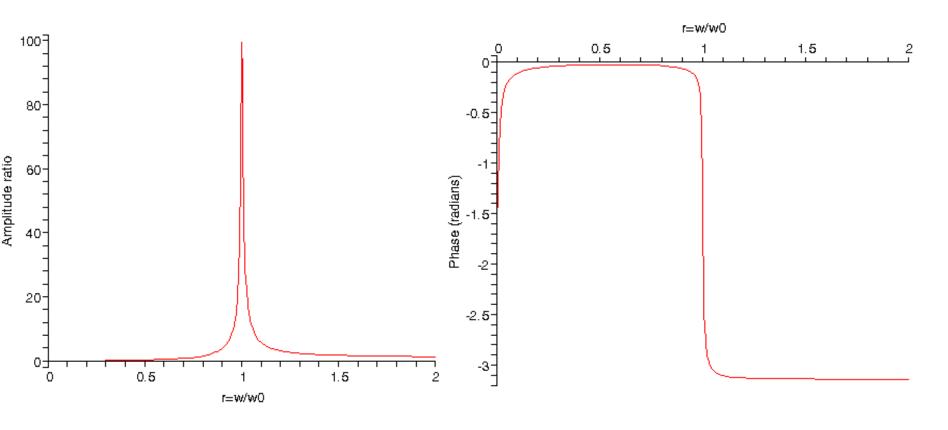
$$\phi_{inertial}(\omega) = \tan^{-1} \left(\frac{Q}{r(1 + Q^2 r^2 - Q^2)}\right)$$

where
$$r = \frac{\omega}{\omega_0}$$

- ω_0 is the natural freq, ω is the drive freq
- Maximum amplitude occurs when $\omega > \omega_0!$
- Base motion amplitude at r=1 is A/Q!



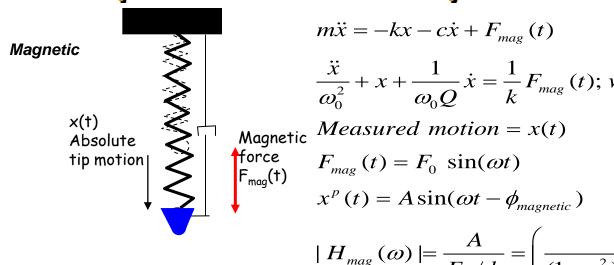
Response of acoustically excited levers



- For Q=100, see response above
- Asymmetric peak, amplitude greater when $\omega > \omega_0$



Response of directly excited AFM levers



$$m\ddot{x} = -kx - c\dot{x} + F_{mag}(t)$$

$$\frac{\ddot{x}}{\omega_0^2} + x + \frac{1}{\omega_0 Q} \dot{x} = \frac{1}{k} F_{mag}(t); with \quad \omega_0 = \sqrt{\frac{k}{m}}, Q = \frac{m\omega_0}{c}$$

$$F_{mag}(t) = F_0 \sin(\omega t)$$
$$x^p(t) = A\sin(\omega t - \phi)$$

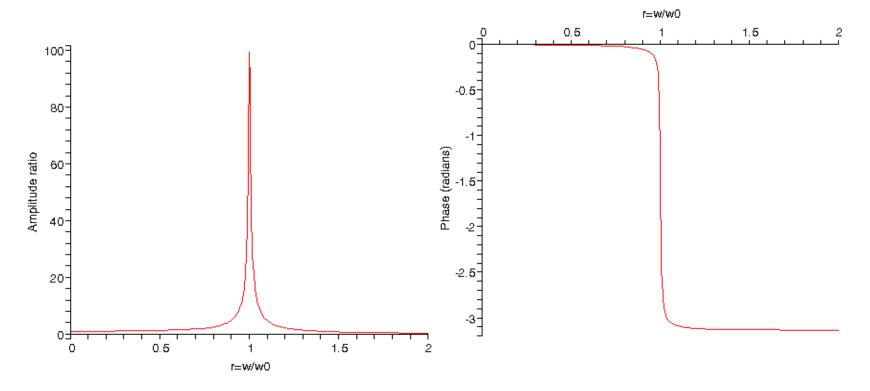
$$|H_{mag}(\omega)| = \frac{A}{F_0 / k} = \left(\frac{1}{(1 - r^2)^2 + (r / Q)^2}\right)^{3/2}$$

$$\phi_{mag}(\omega) = \tan^{-1}\left(\frac{r}{Q(r^2 - 1)}\right)$$
where $r = \frac{\omega}{\omega_0}$

- ω_0 is the natural freq, ω is the drive freq
- Maximum amplitude occurs when $\omega < \omega_0!$
- For $\omega << \omega_0 A = F_{mag}/k!$



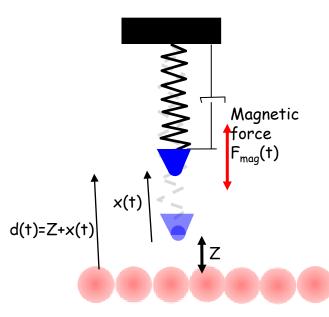
Response of directly excited AFM levers



- Asymmetric response with greater amplitude when $\omega < \omega_0!$
- Classical phase response



Driven point mass model with tip-sample interaction



Magnetic

$$m\ddot{x} = -kx - c\dot{x} + F_{mag}(t) + F_{ts}(Z + x(t))$$

$$\frac{\ddot{x}}{\omega_0^2} + x + \frac{1}{\omega_0 Q} \dot{x} = \frac{1}{k} \Big(F_{mag}(t) + F_{ts}(Z + x(t)) \Big);$$

with
$$\omega_0 = \sqrt{\frac{k}{m}}$$
, $Q = \frac{m\omega_0}{c}$

 $Measured\ motion = x(t)$

$$F_{mag}(t) = F_0 \sin(\omega t)$$

Acoustic excitation

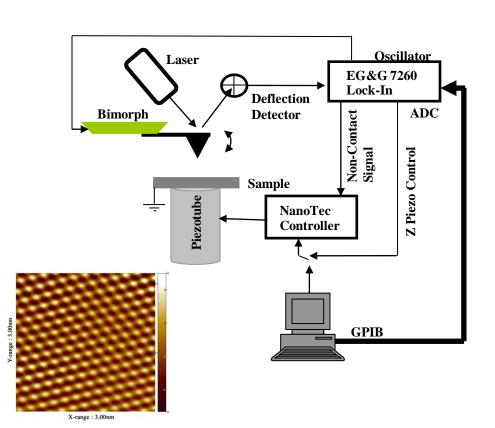
$$\frac{\ddot{z}}{\omega_0^2} + z + \frac{1}{\omega_0 Q} \dot{z} = -\frac{\ddot{y}}{\omega_0^2} - \frac{1}{\omega_0 Q} \dot{y} + \frac{F_{ts} (Z + y(t) + x(t))}{\omega_0^2}$$

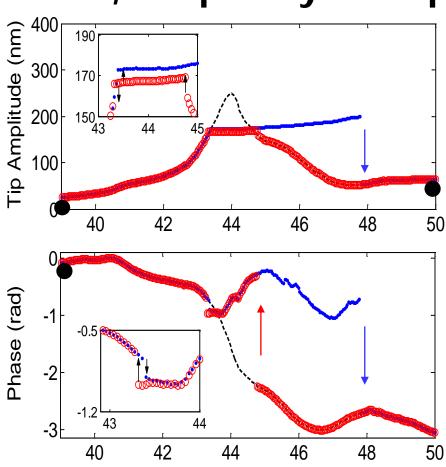
- Highly nonlinear ordinary differential equation
- What happens to frequency response when probe is brought close to sample?



Experiments with conventional tips

Si tip / HOPG sample z=90 nm, frequency sweep





When brought closer to sample the tip sometimes sticks to the sample Lee et al, Phys Rev B (2002)